

N-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^d	Q _g (Typ.)			
100	0.080 at V _{GS} = 10 V	4.5	4.6 nC			
100	0.090 at V _{GS} = 6 V	4.0	4.0 110			

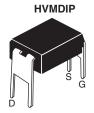
FEATURES

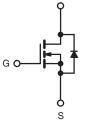
- Trench Power MOSFET
- 100 % UIS Tested

APPLICATIONS

- High Frequency Boost Converter
- LED Backlight for LCD TV







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)					
Parameter	Symbol Limit		Unit		
Drain-Source Voltage		V _{DS}	100	V	
Gate-Source Voltage		V _{GS}	± 20	v	
	T _C = 25 °C	-	4.5		
Continuous Drain Current (T _J = 150 °C)	T _C = 70 °C		3.5		
	T _A = 25 °C	I _D	2.9 ^{a, b}		
	T _A = 70 °C		2.3 ^{a, b}	A	
Pulsed Drain Current		I _{DM}	16		
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	4		
Continuous Source-Drain Diode Current	T _A = 25 °C		2 ^{a, b}		
Single Avalanche Current L = 0.1 mH Single Avalanche Energy L = 0.1 mH		I _{AS}	6	A	
		E _{AS}	1.8	mJ	
	T _C = 25 °C		4.8		
Movimum Dower Dissinction	T _C = 70 °C	– P _D	3	w	
Maximum Power Dissipation	T _A = 25 °C		2.4 ^{a, b}	VV	
	T _A = 70 °C		1.5 ^{a, b}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter	Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	42	53	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	21	26	0/11	

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. t = 10 s.

c. Maximum under steady state conditions is 85 $^\circ\text{C/W}.$

d. Based on T_C = 25 °C.

SPECIFICATIONS (T _J = 25 °C, unless otherwise noted) Parameter Symbol Test Conditions Min. Typ. Max. L						
Static	Symbol	Test Conditions	IVIIII.	тур.	Wax.	Unit
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	100			v
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	GS = 0 1, D = 200 p.1	100	110		- mV/°0
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 7.5		
	. ,	$V_{DS} = V_{GS}$, $I_{D} = 250 \ \mu A$	2	- 7.5	4	v
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $D = 200 \mu$ A $V_{DS} = 0 V$, $V_{GS} = \pm 20 V$	2		4	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$ $V_{DS} = 100 V, V_{GS} = 0 V$			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55 \text{ °C}$			1 10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 100 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$ $V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	8		10	A
	'D(on)	$V_{GS} = 10 \text{ V}, \text{ I}_D = 2.7 \text{ A}$	0	0.080		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 6 V, I_D = 2.5 A$				Ω
Forward Transconductors	a,	$V_{\rm QS} = 0.0$, $I_{\rm D} = 2.7$ A		0.090		S
Forward Transconductance ^a Dynamic ^b	9 _{fs}	VDS = 10 V, 10 = 2.7 A		/		5
Input Capacitance	C _{iss}			370		
Output Capacitance	C _{oss}	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz		40		pF
	C _{oss}	$v_{\rm DS} = 30 v$; $v_{\rm GS} = 0 v$; $r = 1 v_{\rm HZ}$				
Reverse Transfer Capacitance	Orss	V _{DS} = 50 V, V _{GS} = 10 V, I _D = 2.7 A		20	44	
Total Gate Charge	otal Gate Charge Q _g V	$v_{\rm DS} = 50$ V, $v_{\rm GS} = 10$ V, $t_{\rm D} = 2.7$ A		7.1 4.6	11 7	- nC
Gate-Source Charge	Q _{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 6 \text{ V}, I_{D} = 2.7 \text{ A}$		1.7	,	
Gate-Drain Charge	Q _{gd}			2		
Gate Resistance	R _g	f = 1 MHz		3		Ω
Turn-On Delay Time	t _{d(on)}			10	15	
Rise Time	t _r	$V_{DD} = 50 \text{ V}, \text{ R}_{\text{I}} = 23.8 \Omega$		10	15	-
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 2.1 \text{ A}, V_{GEN} = 6 \text{ V}, \text{ R}_q = 1 \Omega$		10	15	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			10	15	ns
Rise Time	t _r	$V_{DD} = 50 \text{ V}, \text{ R}_{1} = 23.8 \Omega$		10	15	-
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 2.1 \text{ A}, \text{ V}_{\text{GEN}} = 10 \text{ V}, \text{ R}_{\text{q}} = 1 \Omega$		12	20	
Fall Time	t _f			10	15	
Drain-Source Body Diode Characteristi						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			4	
Pulse Diode Forward Current	I _{SM}	-			8	A
Body Diode Voltage	V _{SD}	$I_{S} = 2.1 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			50	80	ns
Body Diode Reverse Recovery Charge	Q _{rr}			75	120	nC
Reverse Recovery Fall Time	t _a	$I_F = 2.1 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^\circ\text{C}$		28		
Reverse Recovery Rise Time	-			22		ns

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

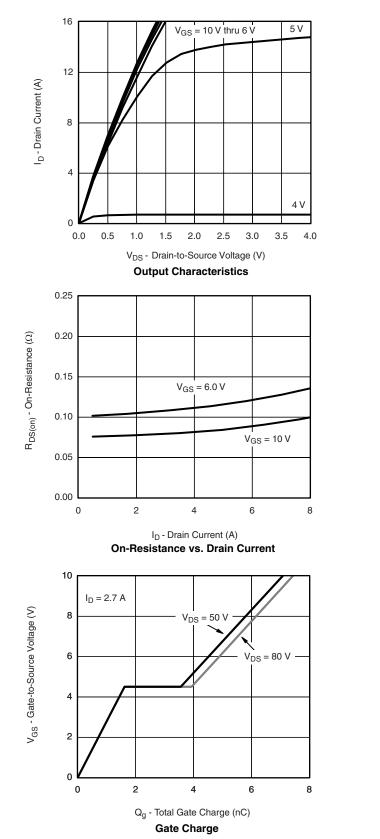
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

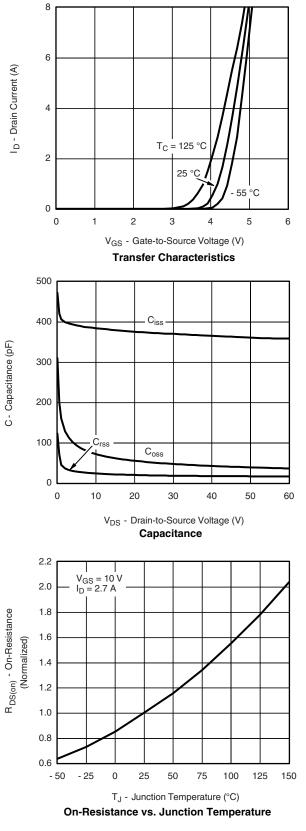
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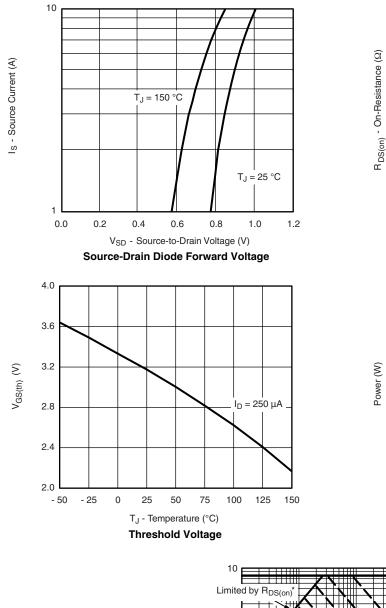


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

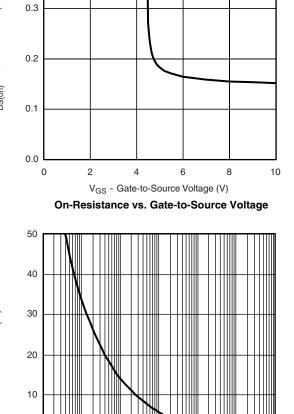




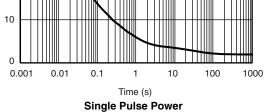
 $I_{D} = 2.7 \text{ A}$

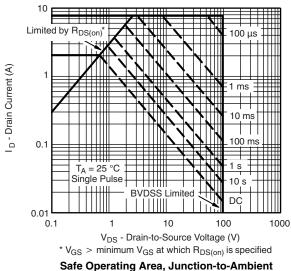


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



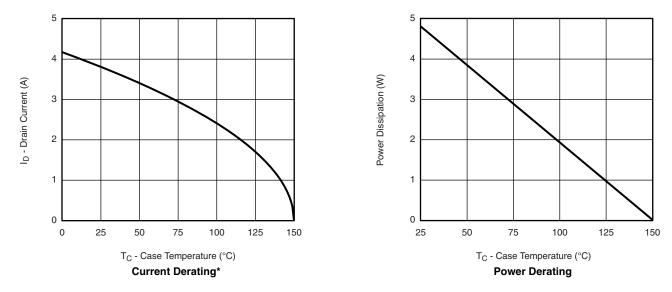
0.4







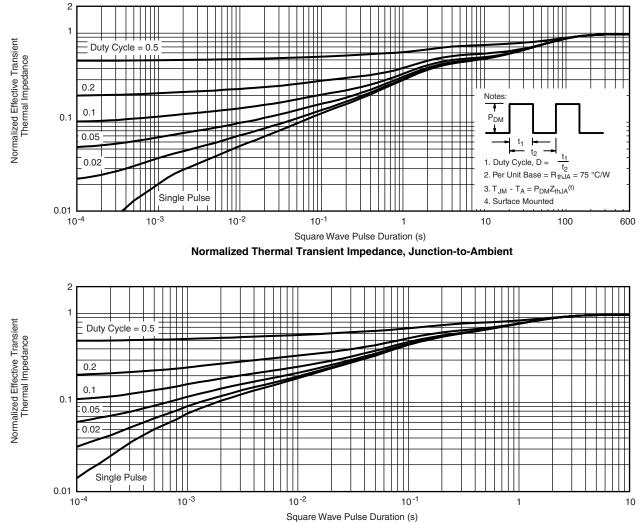
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



* The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



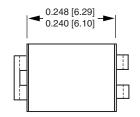


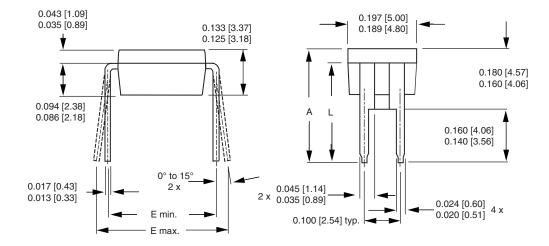


Normalized Thermal Transient Impedance, Junction-to-Foot



HVM DIP (High voltage)





	INCHES		MILLIMETERS		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	0.310	0.330	7.87	8.38	
E	0.300	0.425	7.62	10.79	
L	0.270	0.290	6.86	7.36	
ECN: X10-0386-Rev. B, 00 DWG: 5974	6-Sep-10				

Note

1. Package length does not include mold flash, protrusions or gate burrs. Package width does not include interlead flash or protrusions.



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